## Model 420M3 5mmØ Pyroelectric Laser Detector for UV/Vis/IR



Manufactured under one or more of the following U.S. patents: 3,839,640 - 4,218,620 - 4,326,663 - 4,384,207 - 4,437,003 - 4,441,023 - 4,523,095

**Model 420M3** consists of a single lithium tantalate sensing element sealed into a TO-5 transistor housing with an optical filter. See EltecData #101 for filter selection guide.

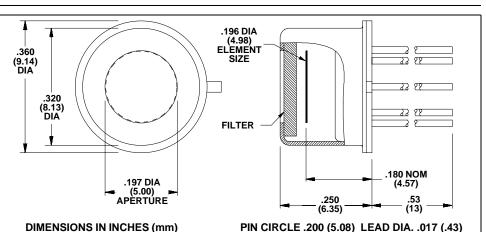
A special element mounting technique is used to heat sink the sensing element, allowing detection at higher power levels.

Because the Model 420M3 is a thermal integrator above the thermal breakpoint, the voltage output falls 20 dB per decade of increasing frequency. Short pulse resolution will be enhanced by using a low value (50 $\Omega$  to 10 K $\Omega$ ) load resistor, which will create a differentiator with the crystal capacitance. This will cancel the detector thermal integration, resulting in a flat frequency response up to the RC 3 dB point.

Another way to achieve a uniform frequency response is to connect the detector to a current to voltage converter (current mode operation). As the detector is connected to the virtual ground of the converter, the load resistance is zero, forming an infinite differentiator with the crystal capacitance. The upper frequency limit is determined by resistance and the shunt capacitance of the converter feedback resistor,  $1/(2\pi R_F C_S)$ . If pulse integration is desired, the detector may be operated in the voltage mode with a high value load resistor  $(1X10^{6}\Omega \text{ to } 1X10^{11}\Omega)$  which will preserve the natural integration of the Rise time and frequency detector. response is dependent on electronics employed. See EltecData # 134 for more information.

## Applications

- Laser Pulse Profile Studies
- Pulse Energy Measurements
- Useful with Monochromatic, Tunable or Multi-Laser Systems
- Laser Power Monitoring (when used with a beamsplitter)
- Millimeter Wave Studies
- UV Laser Detector

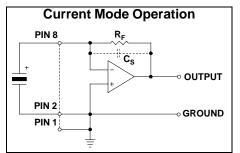


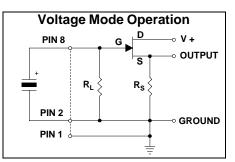
ELTECdata Reference Test Conditions Characteristics 420M3 Unit Detector Type Single Element Size mmØ 4.98 **Optical Bandwidth** 0.1 to 1,000 Various Filters 101 μm (min) 76 **Element Capacitance** pF 140 (max) Current Responsivity 0.25 μA/W 8.3 - 14µm, 10Hz (min) >5 X 10<sup>12</sup> Element Impedance (typ) 0 Thermal Breakpoint f. Hz 102 (typ) 5 Electrical Time 5  $R_1 = 50\Omega$ 102 (typ) ns Constant  $\tau_e$ Incident Power Limit<sup>1</sup> 5 W/cm<sup>2</sup> 109 Recommended -55 to +125 °C Functional **Operating Temperature** Storage Temperature -55 to +125 °C ΔT<50Cº/min °C Curie Temperature 610 Output Protection Short leads together if  $\Delta T$  exceeds 50C°/min

Characteristics at 25°C.

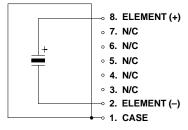
Data is established on a sample basis and is believed to be representative.

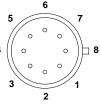
<sup>1</sup>Dependent on pulse width, power & duty cycle.





## PIN DESIGNATIONS





BOTTOM VIEW

For best results, the following precautions and recommendations should be observed. (See ELTECdata # 101):

Mounting: Avoid mechanical stresses on case and leads.

Soldering: Detectors must be hand soldered to minimize the chance of destroying the internal components. Avoid machine or hot air soldering. Leave a minimum lead length of .250 inch (6.35mm). When soldering to detector leads, use a heat sink between the case and leads. Beware that the new RoHS compliant solders require a higher soldering temperature making heat sinking the detector extremely important.

**Static Discharge:** Protect detectors from electro-static charges.

**Optical Filter:** This Model can be used with any standard ELTEC detector filter or used without a filter. For more information, please refer to ELTECdata # 101.

Light Leakage: Slight sensitivity to visible light leaking through the glass-to-metal seal on the base may be observed.

**Polarity:** In current mode operation a positive output for a positive change can be achieved by connecting pin 2 to input of amplifier and pin 8 to ground.

**Noise:** As a resolution or lower information limit, noise is established not only by the detector. Other noise sources are:

- Radiated and conducted RF signals
- Subsequent amplification or signal conditioning stages
- Power supply noise
- Components, such as high value resistors and capacitors (tantalum or aluminum electrolytic)
- · Mechanical contacts and weak solder joints
- · Shock and vibration excited microphonics
- Outside thermal influences on the detector other than the desired infrared input, i.e. drafts

All of these noise sources should be considered carefully when the information signal is <1mV and <20mV for current mode operation.

**Optical Design:** Use of a detector with a filter in an optical system may require consideration of the image displacement toward the filter. This displacement (s) caused by the insertion of a planoparallel plate (filter thickness = t; refractive index = N) is given by s = (t/N)(N-1).

**NOTICE:** The information provided herein is believed to be reliable. However, ELTEC Instruments, Inc. assumes no responsibility for inaccuracies or omissions. Due to industry components being incorporated into ELTEC's devices and ELTEC continually striving for product improvement, specifications may change without notice.



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